

MOS FIELD EFFECT TRANSISTOR μ PA1911

P-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1911 is a switching device which can be driven directly by a 2.5-V power source.

The μ PA1911 features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- Can be driven by a 2.5-V power source
- · Low on-state resistance

 $R_{DS(on)1}$ = 115 $m\Omega$ MAX. (Vgs = -4.5 V, I_D = -1.5 A)

 $R_{DS(on)2} = 120 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = -4.0 \text{ V, Ip} = -1.5 \text{ A)}$

 $R_{DS(on)3} = 190 \text{ m}\Omega \text{ MAX.}$ (Vgs = -2.5 V, ID = -1.0A)

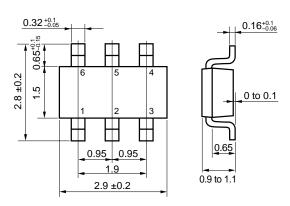
ORDERING INFORMATION

PART NUMBER	PACKAGE
μPA1911TE	6-pin Mini Mold (Thin Type)

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

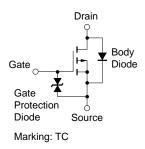
Drain to Source Voltage	Voss	-20	V
Gate to Source Voltage	Vgss	-12/+6	V
Drain Current (DC)	I _{D(DC)}	∓ 2.5	Α
Drain Current (pulse) Note1	ID(pulse)	∓10	Α
Total Power Dissipation	P _{T1}	0.2	W
Total Power Dissipation Note2	P _{T2}	2	W
Channel Temperature	Tch	150	°C
Storage Temperature	T_{stg}	-55 to +150	°C

PACKAGE DRAWING (Unit: mm)



1, 2, 5, 6 : Drain 3 : Gate 4 : Source

EQUIVALENT CIRCUIT



Notes 1. PW \leq 10 μ s, Duty Cycle \leq 1 %

2. Mounted on FR-4 board, $t \le 5$ sec.

Remark The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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The mark ★ shows major revised points.

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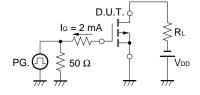
ELECTRICAL CHARACTERISTICS (TA = 25 °C)

CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	V _{DS} = -20 V, V _{GS} = 0 V			-10	μΑ
Gate Leakage Current	Igss	Vgs = ±12 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	$V_{DS} = -10 \text{ V}, \text{ ID} = -1 \text{ mA}$	-0.5	-0.92	-1.5	V
Forward Transfer Admittance	y fs	V _{DS} = -10 V, I _D = -1.5 A	1	4.5		S
Drain to Source On-state Resistance	RDS(on)1	Vgs = -4.5 V, ID = -1.5 A		80	115	mΩ
	RDS(on)2	$V_{GS} = -4.0 \text{ V}, I_{D} = -1.5 \text{ A}$		86	120	mΩ
	RDS(on)3	V _G S = -2.5 V, I _D = -1.0 A		130	190	mΩ
Input Capacitance	Ciss	V _{DS} = -10 V		540		pF
Output Capacitance	Coss	Vss = 0 V		190		pF
Reverse Transfer Capacitance	Crss	f = 1 MHz		90		pF
Turn-on Delay Time	td(on)	V _{DD} = -10 V		140		ns
Rise Time	t r	ID = -1.5 A		500		ns
Turn-off Delay Time	td(off)	$V_{GS(on)} = -4.0 \text{ V}$		420		ns
Fall Time	t f	$R_G = 10 \Omega$		850		ns
Total Gate Charge	Q _G	V _{DD} = -10 V		5.0		nC
Gate to Source Charge	Qgs	ID = -2.5 A		1.5		nC
Gate to Drain Charge	Q _{GD}	Vgs = -4.0 V		2.0		nC
Diode Forward Voltage	V _{F(S-D)}	IF = 2.5 A, VGS = 0 V		0.82		V
Reverse Recovery Time	trr	IF = 2.5 A, Vgs = 0 V		30		ns
Reverse Recovery Charge	Qrr	$di/dt = 10 A/\mu s$		2.0		nC

TEST CIRCUIT 1 SWITCHING TIME

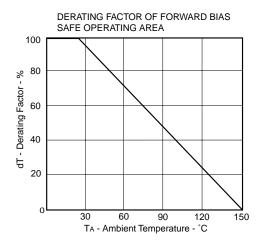
PG. $\bigcap_{R_G} R_G = 10 \Omega$ $\tau = 1 \mu \text{ S}$ Duty Cycle $\leq 1 \%$

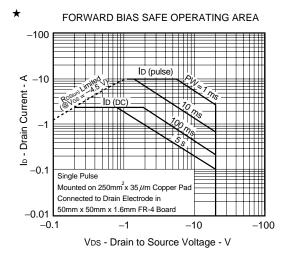
TEST CIRCUIT 2 GATE CHARGE

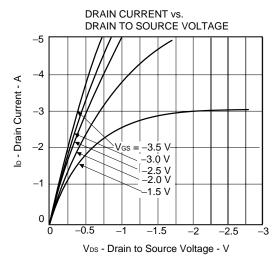


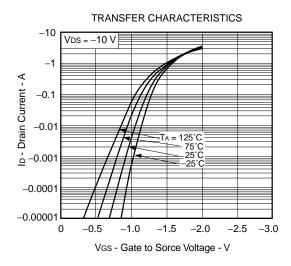


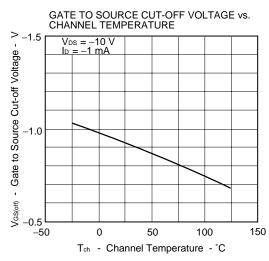
TYPICAL CHARACTERISTICS (TA = 25°C)

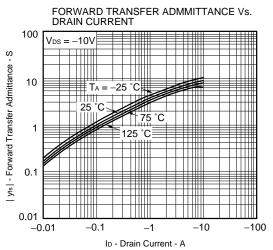




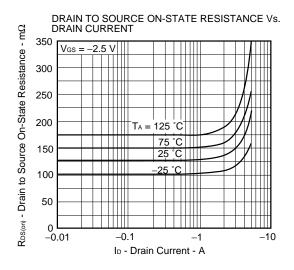


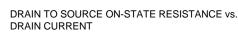


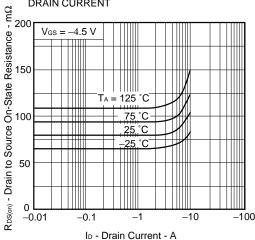




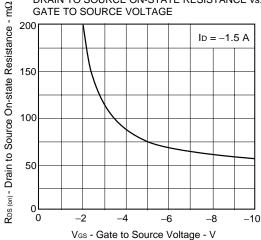
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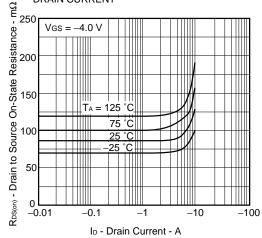




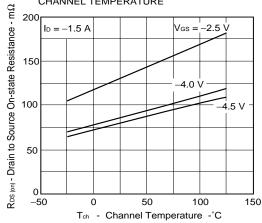
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE



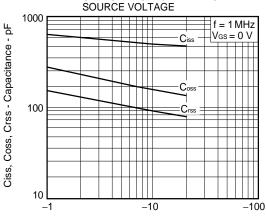
DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**



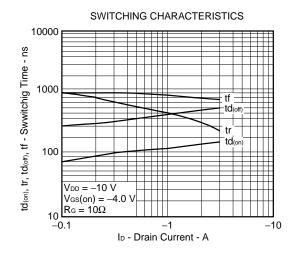
DRAIN TO SOURCE ON STATE RESISTANCE vs. CHANNEL TEMPERATURE

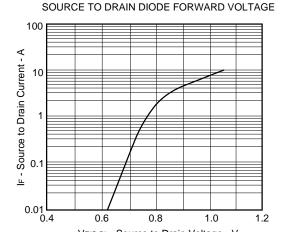


CAPACITANCE vs. DRAIN TO



V_{DS} - Drain to Source Voltage - V





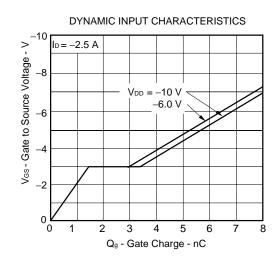
8.0

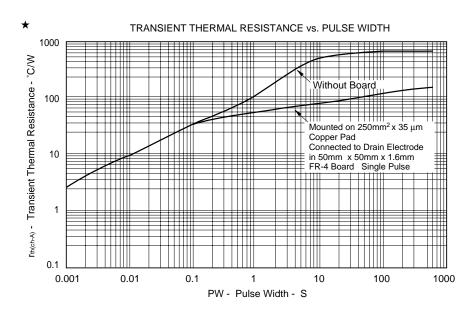
VF(S-D) - Source to Drain Voltage - V

1.0

1.2

0.6





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